

A Space-Mapping Interpolating Surrogate Algorithm for Highly Optimized EM-Based Design of Microwave Devices

John W. Bandler, *Fellow, IEEE*, Daniel M. Hailu, *Student Member, IEEE*, Kaj Madsen, and Frank Pedersen

Abstract—We justify and elaborate in detail on a powerful new optimization algorithm that combines space mapping (SM) with a novel output SM. In a handful of fine-model evaluations, it delivers for the first time the accuracy expected from classical direct optimization using sequential linear programming. Our new method employs a space-mapping-based interpolating surrogate (SMIS) framework that aims at locally matching the surrogate with the fine model. Accuracy and convergence properties are demonstrated using a seven-section capacitively loaded impedance transformer. In comparing our algorithm with major minimax optimization algorithms, the SMIS algorithm yields the same minimax solution within an error of 10^{-15} as the Hald–Madsen algorithm. A highly optimized six-section H -plane waveguide filter design emerges after only four HFSS electromagnetic simulations, excluding necessary Jacobian estimations, using our algorithm with sparse frequency sweeps.

Index Terms—Computer-aided design (CAD) algorithms, electromagnetics, filter design, interpolating surrogate, microwave modeling, optimization, output space mapping (OSM), space mapping (SM), surrogate modeling.

I. INTRODUCTION

ELECTROMAGNETIC (EM) simulators, long used by engineers for design verification, need to be exploited in the optimization process. However, the higher the fidelity (accuracy) of the EM simulations, the more expensive direct optimization becomes. For complex problems, EM direct optimization may be prohibitive. Space mapping (SM) [1] aims to combine the speed and maturity of circuit simulators with the accuracy of EM solvers. The SM concept exploits “coarse” models (usually computationally fast circuit-based models) to construct a surrogate that is faster than the “fine” models (typically CPU-intensive full-wave EM simulations) and at least as accurate as the underlying “coarse” model [1]–[4]. The surrogate is

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iteratively updated by the SM approach to better approximate the corresponding fine model.

From the mathematical motivation of SM [4], it was found that SM-based surrogate models provide a good approximation over a large region, whereas the first-order Taylor model is better close to the optimal fine-model solution. Based on this finding and an explanation of residual misalignment, Bandler *et al.* [5] proposed the novel output space mapping (OSM) to further correct residual misalignment close to the optimal fine-model solution. OSM reduces the number of computationally expensive fine-model evaluations, while improving accuracy of the SM-based surrogate.

This paper elaborates on a new SM algorithm. Highly accurate space-mapping interpolating surrogate (SMIS) models are built for use in gradient-based optimization [6]. The SMIS is required to match both the responses and derivatives of the fine model within a local region of interest. It employs an output mapping to achieve this.

The SMIS framework is formulated in Section IV. An algorithm based on it is outlined in Section V. Convergence is compared with two classical minimax algorithms, and a hybrid aggressive space-mapping (HASM) surrogate-based optimization algorithm using a seven-section capacitively loaded impedance transformer. Finally, the SMIS algorithm is implemented on a six-section H -plane waveguide filter [7].

II. DESIGN PROBLEM

A. Design Problem

The original design problem is

$$\mathbf{x}_f^* = \arg \min_{\mathbf{x}_f} U(\mathbf{R}_f(\mathbf{x}_f)). \quad (1)$$

Here, $\mathbf{R}_f: \mathbb{R}^n \rightarrow \mathbb{R}^m$ is the fine-model response vector, e.g., $|S_{11}|$ at selected frequency points $\omega_i, i = 1, \dots, m, m$ is the number of response sample points, and the fine-model point is denoted $\mathbf{x}_f \in \mathbb{R}^n$, where n is the number of design parameters. $U: \mathbb{R}^m \rightarrow \mathbb{R}$ is a suitable objective function, and $\mathbf{x}_f^* \in \mathbb{R}^n$ is the optimal design.

III. OSM

OSM addresses residual misalignment between the optimal coarse-model response and the true fine-model optimum response $\mathbf{R}_f(\mathbf{x}_f^*)$. In the original SM [1], an exact match between

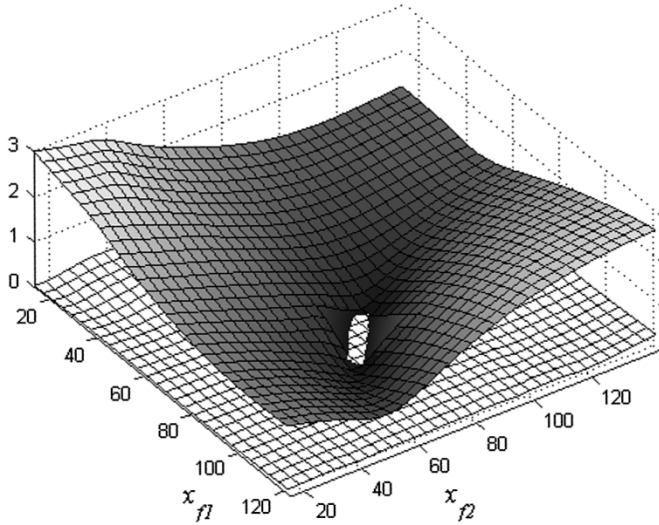


Fig. 1. Error plots for a two-section capacitively loaded impedance transformer [4] exhibiting the quasi-global effectiveness of SM (light grid) versus a classical Taylor approximation (dark grid). See text.

the fine model and mapped coarse model is unlikely. For example, a coarse model such as $R_c = x^2$ will never match the fine model $R_f = x^2 - 2$ around its minimum with any mapping $x_c = P(x_f)$, $x_c, x_f \in \mathbb{R}$. An “output” or response mapping can overcome this deficiency by introducing a transformation of the coarse-model response based on a Taylor approximation [8].

The results of Bakr *et al.* [4] indicate that “input” SM-based surrogates are good approximations to the fine model over a large region, which makes them useful in the early stages of an optimization process. The residual misalignment between the corresponding mapped coarse model(s) and the fine model renders an exact match between them unlikely. Consequently, convergence to \mathbf{x}_f^* should not be expected.

Fig. 1 depicts model effectiveness plots [4] for a two-section capacitively loaded impedance transformer at the final iterate $\mathbf{x}_f^{(i)}$, approximately $[74.23 \ 79.27]^T$. Centered at $\mathbf{h} = \mathbf{0}$, the light grid shows $\|R_f(\mathbf{x}_f^{(i)} + \mathbf{h}) - R_c(L_p(\mathbf{x}_f^{(i)} + \mathbf{h}))\|$. This represents the deviation of the mapped coarse model (using the Taylor approximation $L_p : \mathbb{R}^n \rightarrow \mathbb{R}^n$ to the mapping, i.e., a linearized mapping) from the fine model. The dark grid shows $\|R_f(\mathbf{x}_f^{(i)} + \mathbf{h}) - L_f(\mathbf{x}_f^{(i)} + \mathbf{h})\|$. This is the deviation of the fine model from its classical Taylor approximation $L_f : \mathbb{R}^n \rightarrow \mathbb{R}^m$. The gradient of the two-section capacitively loaded impedance transformer, used in the Taylor approximation, was obtained analytically using the adjoint network method [9]. The light grid surface passing over the dark grid surface near the center of Fig. 1 verifies that the Taylor approximation is most accurate close to $\mathbf{x}_f^{(i)}$, whereas the mapped coarse model is best over a larger region. The reason that the Taylor approximation is best in the vicinity of $\mathbf{x}_f^{(i)}$ is that the Taylor approximation interpolates at the development point, whereas the mapped coarse model does not.

Based on the above finding, Bakr *et al.* [10] use a surrogate that is a convex combination of a mapped coarse model and a first-order Taylor approximation of the fine model. Madsen and Søndergaard [11] prove convergence of such HASM algorithms.

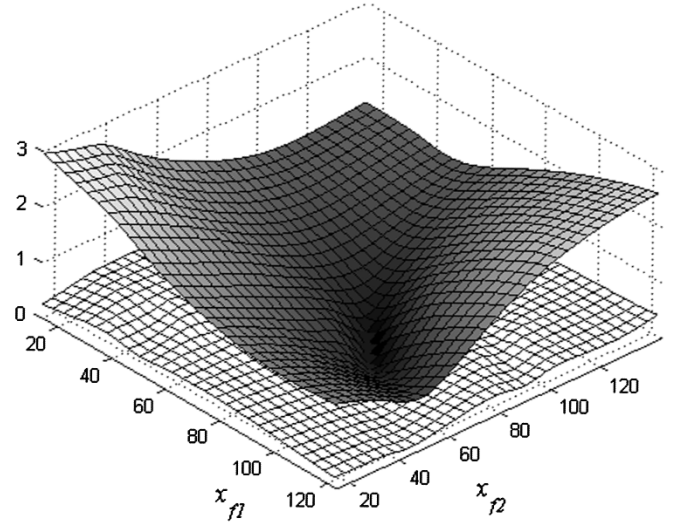


Fig. 2. Error plots for a two-section capacitively loaded impedance transformer [4] exhibiting the quasi-global effectiveness of SM-based interpolating surrogate, which exploits OSM (light grid) versus a classical Taylor approximation (dark grid). See text.

In this paper, we introduce a novel method to ensure convergence of the SM technique. OSM is incorporated into SMIS to ensure that we obtain the same solution as classical direct gradient-based optimization. Fig. 2 depicts model effectiveness plots for the two-section capacitively loaded impedance transformer corresponding to Fig. 1. Centered at $\mathbf{h} = \mathbf{0}$, the light grid shows $\|R_f(\mathbf{x}_f^{(i)} + \mathbf{h}) - R_s(\mathbf{x}_f^{(i)} + \mathbf{h})\|$. This represents the deviation of the SMIS surrogate from the fine model. The dark grid shows the deviation of the fine model from its classical Taylor approximation as in Fig. 1. Thus, Fig. 2 demonstrates that the SMIS surrogate, because of its interpolating properties, performs better than the first-order Taylor approximation even close to $\mathbf{x}_f^{(i)}$.

IV. SMIS FRAMEWORK

A. Surrogate

The SM-based interpolating surrogate $R_s : \mathbb{R}^n \rightarrow \mathbb{R}^m$ is defined as a transformation of a coarse model $R_c : \mathbb{R}^n \rightarrow \mathbb{R}^m$ through input and output mappings at each sampled response. Fig. 3 illustrates the SMIS framework. Here, $P = [P_1 \dots P_m]^T$, where $P_i : \mathbb{R}^n \rightarrow \mathbb{R}^n, i = 1, \dots, m$, [1], [2] is an input mapping for the i th coarse response $R_{c,i}$, and $O : \mathbb{R}^m \rightarrow \mathbb{R}^m$ [8] is an output mapping applied to the coarse response. Using the function $R_p : \mathbb{R}^{m \cdot n} \rightarrow \mathbb{R}^m$ with individually adjusted coarse responses, defined as $R_p(\mathbf{z}_1, \dots, \mathbf{z}_m) = [R_{c,1}(\mathbf{z}_1) \dots R_{c,m}(\mathbf{z}_m)]^T$, where $\mathbf{z}_i \in \mathbb{R}^n, i = 1, \dots, m$, the surrogate can be expressed as a composed mapping $R_s = O \circ R_p \circ P$.

We wish to consider individual mappings of each coarse response $R_{c,i}, i = 1, \dots, m$. These (nonlinear) mappings will be approximated by a sequence of local linear mappings. The i th linearized input mapping at the j th iteration is assumed to be of the form

$$P_i(\mathbf{x}_f) = B_i \mathbf{x}_f + \mathbf{c}_i \quad (2)$$

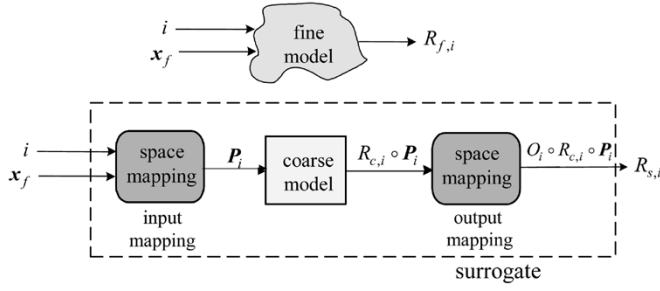


Fig. 3. Illustration of the SMIS concept. The aim is to calibrate the mapped coarse model (the surrogate) to match the fine model using different input and output mappings for each sampled response.

where the matrix $\mathbf{B}_i \in \mathbb{R}^{n \times n}$ and vector $\mathbf{c}_i \in \mathbb{R}^n$. The i th output mapping is defined as

$$O_i(\mathbf{y}) = \alpha_i(y_i - \bar{y}_i) + \beta_i \quad (3)$$

where y_i, \bar{y}_i are the i th components of $\mathbf{y}, \bar{\mathbf{y}} \in \mathbb{R}^m$. \bar{y}_i is defined as $\bar{y}_i = R_{c,i}(\mathbf{B}_i \bar{\mathbf{x}}_f + \mathbf{c}_i)$, where $\bar{\mathbf{x}}_f$ is a constant vector. Defining y_i similarly, the i th component of the surrogate becomes

$$\begin{aligned} R_{s,i}(\mathbf{x}_f) &= O_i\left(R_p(P_i(\mathbf{x}_f))\right) \\ &= \alpha_i(R_{c,i}(\mathbf{B}_i \mathbf{x}_f + \mathbf{c}_i) - R_{c,i}(\mathbf{B}_i \bar{\mathbf{x}}_f + \mathbf{c}_i)) + \beta_i. \end{aligned} \quad (4)$$

We now discuss how to determine the constants $\{\mathbf{B}_i, \mathbf{c}_i, \alpha_i, \beta_i\}, i = 1, \dots, m$ defining the linear mappings O and P . Assume we have reached the j th iterate $\mathbf{x}_f^{(j)}$ in the iterative search for a solution. At $\mathbf{x}_f^{(j)}$, the surrogate $\mathbf{R}_s^{(j)}$ must agree with the fine response [12]

$$\mathbf{R}_s^{(j)}(\mathbf{x}_f^{(j)}) = \mathbf{R}_f(\mathbf{x}_f^{(j)}). \quad (5)$$

We also aim to align the surrogate with the fine-model response at the previous points in the iteration, as well as aim to have agreement between the Jacobians at the current point, i.e.,

$$\begin{aligned} \mathbf{R}_s^{(j)}(\mathbf{x}_f^{(k)}) &= \mathbf{R}_f(\mathbf{x}_f^{(k)}), \quad k = 1, 2, \dots, j-1 \\ \mathbf{J}_s^{(j)}(\mathbf{x}_f^{(j)}) &= \mathbf{J}_f(\mathbf{x}_f^{(j)}) \end{aligned} \quad (6)$$

where $\mathbf{J}_s^{(j)}(\mathbf{x}_f^{(j)})$ and $\mathbf{J}_f(\mathbf{x}_f^{(j)})$ are the Jacobians of the surrogate and fine model at $\mathbf{x}_f^{(j)}$, respectively.

The constants $\{\mathbf{B}_i, \mathbf{c}_i, \alpha_i, \beta_i\}, i = 1, \dots, m$ are determined in such a way that the alignment (5) holds and the requirements in (6) are satisfied as well as possible (in some sense to be specified). The alignment (5) is satisfied by choosing $\bar{\mathbf{x}}_f$ and β_i appropriately. If we let $\bar{\mathbf{x}}_f = \mathbf{x}_f^{(j)}$, then (5) only depends on the choice of β_i .

Thus, the j th surrogate of response number i is

$$\begin{aligned} R_{s,i}^{(j)}(\mathbf{x}_f) &= \alpha_i^{(j)} \left(R_{c,i}(P_i^{(j)}(\mathbf{x}_f)) \right. \\ &\quad \left. - R_{c,i}(P_i^{(j)}(\mathbf{x}_f^{(j)})) \right) + \beta_i^{(j)}, \\ i &= 1, \dots, m \text{ and } j = 0, 1, \dots \end{aligned} \quad (7)$$

where

$$P_i^{(j)}(\mathbf{x}_f) = \mathbf{B}_i^{(j)} \mathbf{x}_f + \mathbf{c}_i^{(j)}. \quad (8)$$

In the first iteration, the mapping parameters $\mathbf{B}_i^{(0)} = \mathbf{I}, \mathbf{c}_i^{(0)} = 0, \alpha_i^{(0)} = 1$ and $\beta_i^{(0)} = \alpha_i^{(0)} R_{c,i}(P_i^{(0)}(\mathbf{x}_f^{(0)}))$ are used, which ensure that $\mathbf{R}_s^{(0)}(\mathbf{x}_f) = \mathbf{R}_c(\mathbf{x}_f)$. For $j > 0$, the parameter $\beta_i^{(j)} = R_f(\mathbf{x}_f^{(j)})$ is utilized, which ensures (5).

In summary, the surrogate used in the j th iteration is given by

$$\mathbf{R}_s^{(j)}(\mathbf{x}_f) = \left[R_{s,1}^{(j)}(\mathbf{x}_f) \dots R_{s,m}^{(j)}(\mathbf{x}_f) \right]^T. \quad (9)$$

In each iteration, the surrogate is optimized to find the next iterate by solving

$$\mathbf{x}_f^{(j+1)} = \arg \min_{\mathbf{x}_f} U\left(\mathbf{R}_s^{(j)}(\mathbf{x}_f)\right). \quad (10)$$

B. Surface Fitting Approach for Parameter Extraction (PE)

PE is a crucial step in any SM algorithm. In this paper, we employ a surface fitting approach for PE, which involves the minimization of residuals between the surrogate and fine models, and extracting the parameters $\mathbf{B}_i^{(j+1)}, \mathbf{c}_i^{(j+1)}$, and $\alpha_i^{(j)}, i = 1, \dots, m$.

Assume $\mathbf{x}_f^{(j+1)}$ has been found. We now wish to find the $(j+1)$ th set of mapping parameters $\{\alpha_i^{(j+1)}, \mathbf{B}_i^{(j+1)}, \mathbf{c}_i^{(j+1)}\}$. Since (5) is automatically satisfied by using (7), the aim is to ensure the matching (6). Thus, for finding $\{\alpha_i^{(j+1)}, \mathbf{B}_i^{(j+1)}, \mathbf{c}_i^{(j+1)}\}$, we aim to minimize the following set of residuals in some sense [6]:

$$\begin{aligned} \mathbf{r}_i^{(j+1)}(\alpha, \mathbf{B}, \mathbf{c}) &\triangleq \begin{bmatrix} R_{s,i}^{(j+1)}(\mathbf{x}_f^{(1)}, \alpha, \mathbf{B}, \mathbf{c}) - R_{f,i}(\mathbf{x}_f^{(1)}) \\ \vdots \\ R_{s,i}^{(j+1)}(\mathbf{x}_f^{(j)}, \alpha, \mathbf{B}, \mathbf{c}) - R_{f,i}(\mathbf{x}_f^{(j)}) \\ \mathbf{J}_{s,i}^{(j+1)}(\mathbf{x}_f^{(j+1)}, \alpha, \mathbf{B}, \mathbf{c}) - \mathbf{J}_{f,i}(\mathbf{x}_f^{(j+1)}) \end{bmatrix} \end{aligned} \quad (11)$$

where $\mathbf{J}_{f,i}$ and $\mathbf{J}_{s,i}$ are the i th columns of \mathbf{J}_f^T and \mathbf{J}_s^T , respectively. The residual (11) is used during the PE optimization process

$$\left\{ \alpha_i^{(j+1)}, \mathbf{B}_i^{(j+1)}, \mathbf{c}_i^{(j+1)} \right\} = \arg \min_{\alpha, \mathbf{B}, \mathbf{c}} \left\| \mathbf{r}_i^{(j+1)}(\alpha, \mathbf{B}, \mathbf{c}) \right\| \quad (12)$$

which extracts the mapping parameters for the i th response, and for iteration $j+1$. Hence, we have the complete set of mapping parameters after m PE optimizations.

V. PROPOSED SMIS ALGORITHM

Our proposed algorithm begins with the coarse model as the initial surrogate. The algorithm incorporates explicit SM [1] and OSM [5] to speed up the convergence to the optimal solution.

- Step 1) Select a coarse and fine model.
- Step 2) Set $j = 0$, and initialize $\mathbf{x}_f^{(0)}$.

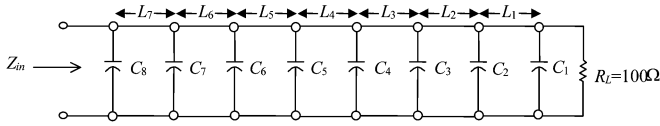


Fig. 4. Seven-section capacitively loaded impedance transformer: “Fine” model.

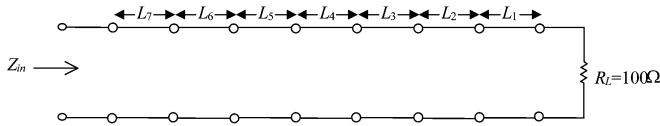


Fig. 5. Seven-section capacitively loaded impedance transformer: “Coarse” model.

TABLE I
FINE MODEL CAPACITANCES, AND THE CHARACTERISTIC IMPEDANCES FOR THE SEVEN-SECTION CAPACITIVELY LOADED IMPEDANCE TRANSFORMER

Capacitance	Value (pF)	Impedance	Value (Ohm)
C_1	0.025	Z_1	91.9445
C_2	0.025	Z_2	85.5239
C_3	0.025	Z_3	78.1526
C_4	0.025	Z_4	70.7107
C_5	0.025	Z_5	63.9774
C_6	0.025	Z_6	58.4632
C_7	0.025	Z_7	54.3806
C_8	0.025		

- Step 3) Optimize the surrogate (9) to find the next iterate $\mathbf{x}_f^{(j+1)}$ by solving (10).
- Step 4) Evaluate $\mathbf{R}_f(\mathbf{x}_f^{(j+1)})$, $\mathbf{J}_f(\mathbf{x}_f^{(j+1)})$.
- Step 5) Terminate if the stopping criteria are satisfied.
- Step 6) Update the input and output mapping parameters $\alpha_i^{(j+1)}$, $\mathbf{B}_i^{(j+1)}$, $\mathbf{c}_i^{(j+1)}$, $i = 1, \dots, m$ through PE by solving (12).
- Step 7) Set $j = j + 1$, and go to Step 3.

As stopping criteria for the algorithm in Step 5, the relative change in the solution vector, or the relative change in the objective function, could be employed.

VI. EXAMPLES

A. Seven-Section Capacitively Loaded Impedance Transformer

We consider the benchmark synthetic example of a seven-section capacitively loaded impedance transformer [4]. We apply the proposed SMIS algorithm to that example. The objective function is given by $U_f = \max_{1 \leq i \leq m} |S_{11,i}|$. We consider a “coarse” model as an ideal seven-section transmission line (TL), where the “fine” model is a capacitively loaded TL with capacitors $C_{1,\dots,8} = 0.025$ pF. The fine and coarse models are shown in Figs. 4 and 5, respectively. Design parameters are normalized lengths $\mathbf{x}_f = [L_1 \ L_2 \ L_3 \ L_4 \ L_5 \ L_6 \ L_7]^T$ with respect to the quarter-wave length L_q at the center frequency of 4.35 GHz. Design specifications are

$$|S_{11}| \leq 0.07, \quad \text{for } 1 \text{ GHz} \leq \omega \leq 7.7 \text{ GHz} \quad (13)$$

with 68 points per frequency sweep. The characteristic impedances for the transformer are fixed as shown in Table I. The

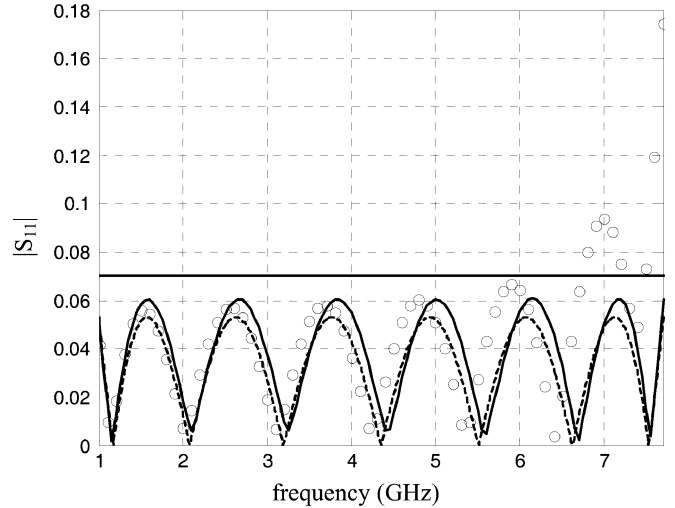


Fig. 6. Seven-section capacitively loaded impedance transformer: optimal coarse-model response (---), the optimal minimax fine-model response (—), and the fine-model response at the initial solution or at the optimal coarse-model solution (o).

TABLE II
OPTIMIZABLE PARAMETER VALUES OF THE SEVEN-SECTION CAPACITIVELY LOADED IMPEDANCE TRANSFORMER

Parameter	Initial solution (m)	Solution reached by the SMIS algorithm (m)	Solution obtained by direct optimization (m)
L_1	0.01724138	0.01564205	0.01564205
L_2	0.01724138	0.01638347	0.01638347
L_3	0.01724138	0.01677145	0.01677145
L_4	0.01724138	0.01697807	0.01697807
L_5	0.01724138	0.01709879	0.01709879
L_6	0.01724138	0.01723238	0.01723238
L_7	0.01724138	0.01625988	0.01625988

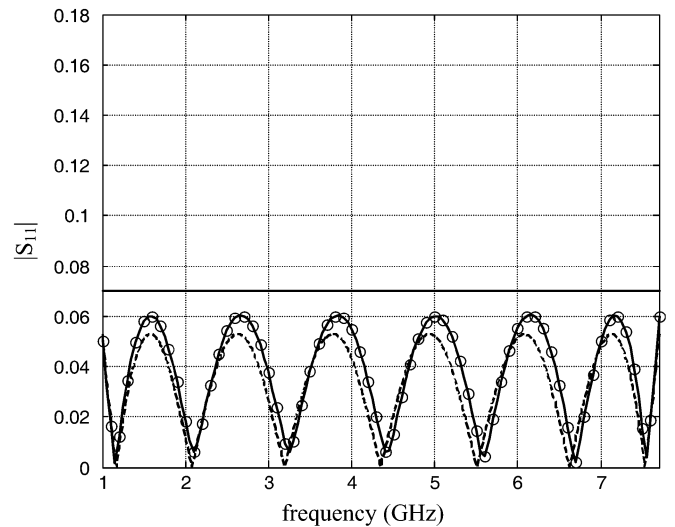


Fig. 7. Seven-section capacitively loaded impedance transformer: optimal coarse-model response (---), the optimal minimax fine-model response (—), and the fine-model response at the SMIS algorithm solution obtained after five iterations (six fine-model evaluations) (o).

Jacobians of both the coarse and fine models were obtained analytically using the adjoint network method [9]. We solve

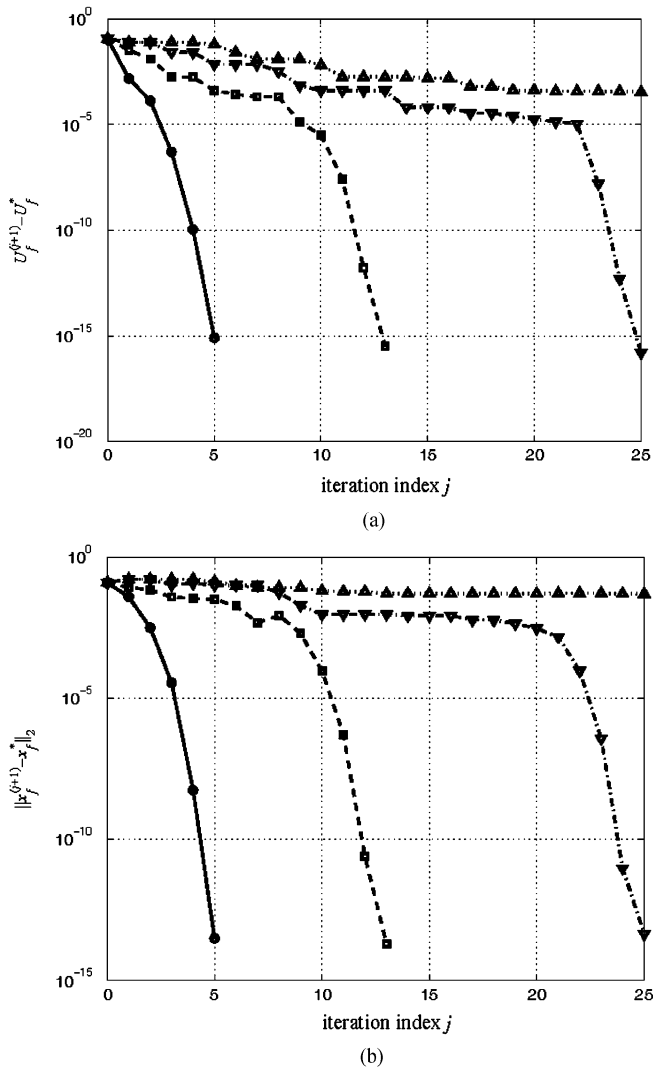


Fig. 8. (a) First 25 iterations of the difference between the fine-model objective function U_f obtained using the SMIS algorithm (\circ) and the fine-model objective function at the fine-model minimax solution U_f^* obtained by the Hald–Madsen algorithm (\square), the HASM surrogate optimization algorithm using exact gradients (∇), and the HASM surrogate optimization algorithm using the Broyden update (Δ). (b) The corresponding difference between the designs.

the PE problem using the Levenberg–Marquardt algorithm for nonlinear least squares optimization available in the MATLAB Optimization Toolbox.¹

Optimizing the fine model directly using the gradient-based minimax method of Madsen [13], and Hald and Madsen [14] confirms that the problem has numerous local solutions. Starting from the optimal coarse-model solution (the initial solution for the SMIS method), the Hald–Madsen minimax algorithm needs 13 iterations, or 13 fine-model evaluations, to converge to the fine-model minimax solution. Note that both the direct optimization method of Hald and Madsen and the SMIS approach employ exact gradients.

The fine-model response at the optimal coarse-model solution is shown in Fig. 6. Table II shows the lengths for solutions obtained using the SMIS algorithm and the fine-model direct minimax optimization solution [13], [14]. Our SMIS algorithm

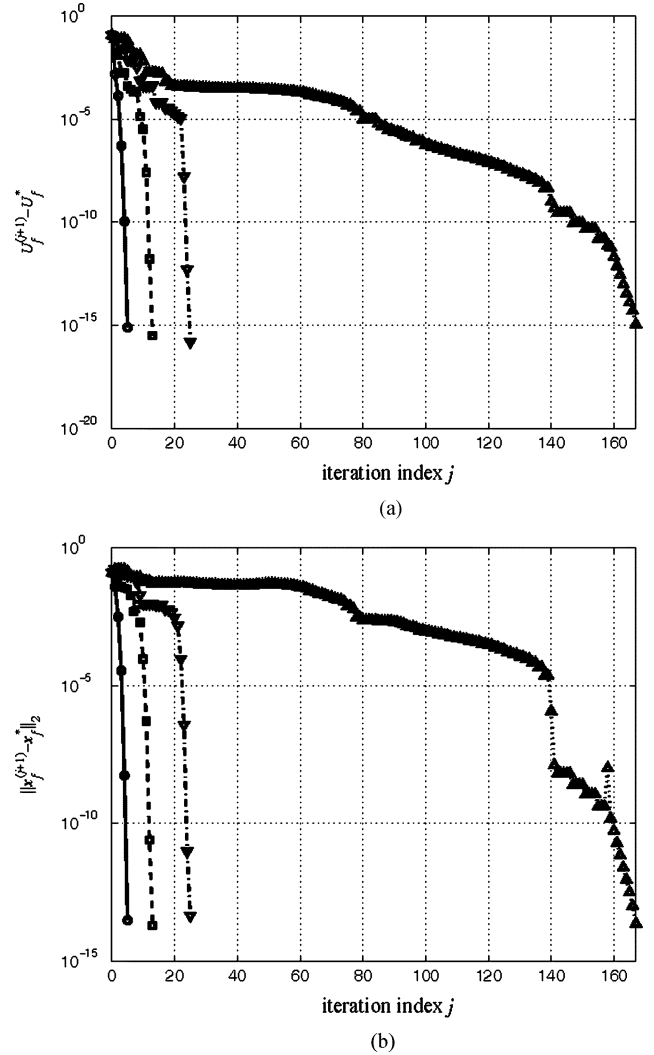


Fig. 9. (a) Difference between the fine-model objective function U_f obtained using the SMIS algorithm (\circ) and the fine-model objective function at the fine-model minimax solution U_f^* obtained by the Hald–Madsen algorithm (\square), the HASM surrogate optimization algorithm using exact gradients (∇), and the HASM surrogate optimization algorithm using the Broyden update (Δ). (b) The corresponding difference between the designs.

took six fine-model evaluations or five iterations to reach the same accurate solution as the Hald–Madsen direct minimax optimization algorithm.

Fig. 7 shows the fine-model response at the SMIS algorithm solution. The difference between the minimax objective function at the optimal minimax fine-model response and the response obtained using the SMIS algorithm is shown in Figs. 8 and 9.

Corresponding results reached by the Hald–Madsen method are shown in Figs. 8 and 9. In these figures, we show the HASM surrogate exploiting exact gradients. The minimax objective function and solution reached by the HASM surrogate optimization approach using the Broyden update [10] are also shown. The four methods converged to the same highly accurate solution.

The optimization methods used for solving (1) and a comparison is shown in Table III. Using the adjoint technique, the SMIS algorithm was able to obtain the same optimum solution as the Hald–Madsen algorithm within an error of 10^{-15} after only five iterations.

¹MATLAB, ver. 6.1, MathWorks Inc., Natick, MA, 2001.

TABLE III
OPTIMIZATION METHODS USED ON THE SEVEN-SECTION
CAPACITIVELY LOADED IMPEDANCE TRANSFORMER

Problem	Method	Number of Iterations	Number of fine model evaluations
(1)	fminimax*	14	153
	HASM	25	26
	Hald-Madsen	13	13
	SMIS	5	6

* The fminimax routine available in the Matlab Optimization Toolbox [13].

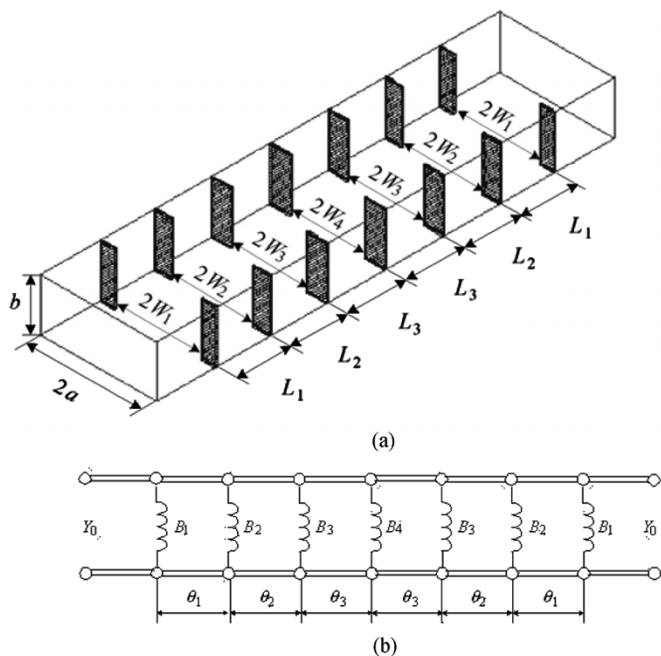


Fig. 10. Six-section *H*-plane waveguide filter [7]. (a) Physical structure. (b) Coarse model as implemented in MATLAB.

In contrast to SMIS, the standard minimax optimizer available in MATLAB was able to reach the same optimum direct optimization result in 14 iterations (153 fine-model evaluations), while the Hald-Madsen algorithm reached the optimum fine-model solution in 13 iterations (13 fine-model evaluations). The HASM algorithm exploiting exact gradients took 25 iterations (26 fine-model evaluations) to reach the optimum fine-model solution to the same error of 10^{-15} .

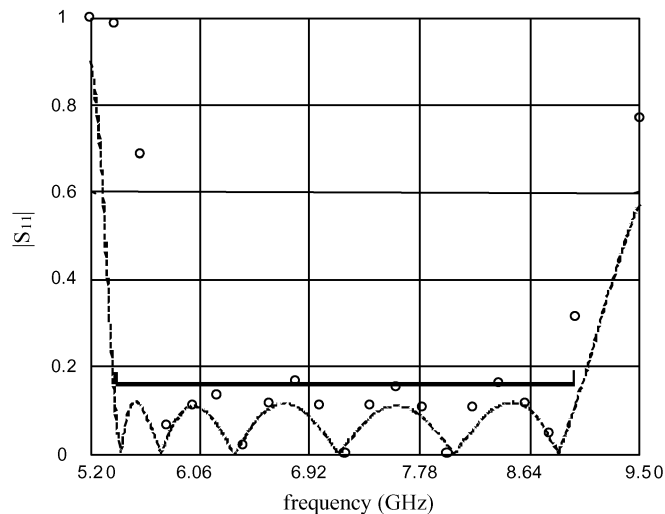
The Hald-Madsen algorithm exploits sequential linear programming (SLP) using trust regions, combined with a Newton iteration. The MATLAB minimizer (*fminimax*) exploits a sequential quadratic programming (SQP) method with line searches.

B. Six-Section *H*-Plane Waveguide Filter

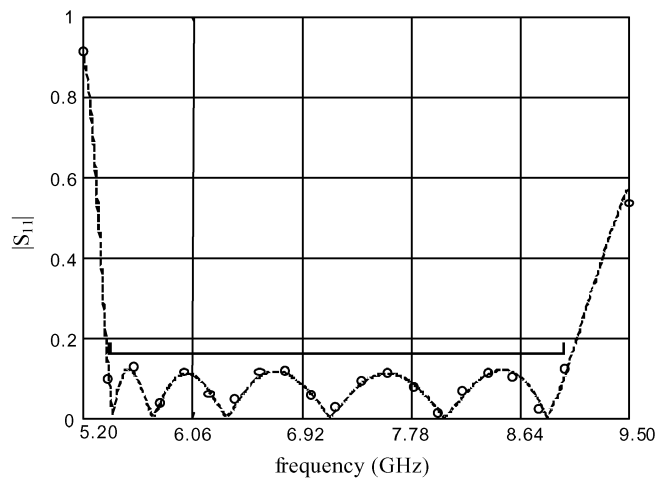
The physical structure of the six-section *H*-plane waveguide filter is shown in Fig. 10(a) [7]. We simulate the fine model using Agilent High Frequency Structure Simulator (HFSS).² The design parameters are the lengths and widths, namely,

$$\mathbf{x}_f = [L_1 \ L_2 \ L_3 \ W_1 \ W_2 \ W_3 \ W_4]^T.$$

²Agilent HFSS, ver. 5.6, HP EESof, Agilent Technol., Santa Rosa, CA, 2000.



(a)



(b)

Fig. 11. *H*-plane filter optimal coarse-model response (—), and the HFSS (fine-model) response: (a) at the initial solution (o) and (b) at the SMIS algorithm solution reached after three iterations (o).

TABLE IV
OPTIMIZABLE PARAMETER VALUES OF THE SIX-SECTION
H-PLANE WAVEGUIDE FILTER

Parameter	Initial solution (inches)	Solution reached by the SMIS algorithm (inches)
W_1	0.48583	0.51397
W_2	0.43494	0.47244
W_3	0.40433	0.44501
W_4	0.39796	0.44627
L_1	0.65585	0.63142
L_2	0.65923	0.63922
L_3	0.67666	0.65705

Design specifications are

$$\begin{aligned} |S_{11}| &\leq 0.16, & \text{for } 5.4 \text{ GHz} \leq \omega \leq 9.0 \text{ GHz} \\ |S_{11}| &\geq 0.85, & \text{for } \omega \leq 5.2 \text{ GHz} \\ |S_{11}| &\geq 0.5, & \text{for } \omega \geq 9.5 \text{ GHz} \end{aligned}$$

with 23 points per frequency sweep.

A waveguide with a cross section of 1.372 in \times 0.622 in (3.485 cm \times 1.58 cm) is used. The six sections are separated by

seven H -plane septa, which have a finite thickness of 0.02 in (0.508 mm). The coarse model consists of lumped inductances and dispersive TL sections [see Fig. 10(b)]. There are various approaches to calculate the equivalent inductive susceptance of an H -plane septum. We use a simplified version of a formula due to Marcuvitz [15]. The coarse model is simulated using MATLAB. The fine model exploits the Agilent HFSS simulator. One frequency sweep takes 2.5 min on an Intel Pentium 4 (3 GHz) machine with 1-GB RAM and running in Windows XP Pro. Seven fine-model simulations, due to the seven 0.01-in perturbations, are required to find the fine-model Jacobian offline using the finite-difference method. Thus, the time taken for fine model and Jacobian calculation is 21 min/iteration on an Intel P4 machine. Fig. 11(a) shows the fine-model response at the initial solution. Fig. 11(b) shows the fine-model response after running our SMIS algorithm using HFSS. The total time taken was 126 min on an Intel P4 3-GHz machine. Table IV shows the initial and optimal design parameter values of the six-section H -plane waveguide filter.

VII. CONCLUSION

We have presented a powerful algorithm based on a novel SMIS framework that delivers the solution accuracy expected from direct gradient-based optimization using SLP, yet converges in a handful of iterations. It aims at matching a surrogate (mapped coarse model) with the fine model within a local region of interest by introducing more degrees of freedom into the SM. Convergence is demonstrated through a seven-section capacitively loaded impedance transformer. We compare the SMIS algorithm with major direct minimax optimization algorithms. It yields the same solution within an error of 10^{-15} as the Hald–Madsen algorithm. A highly optimized H -plane filter design emerges after only four EM simulations (three iterations), excluding necessary Jacobian estimations, using the new algorithm with sparse frequency sweeps.

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